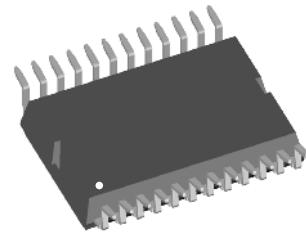
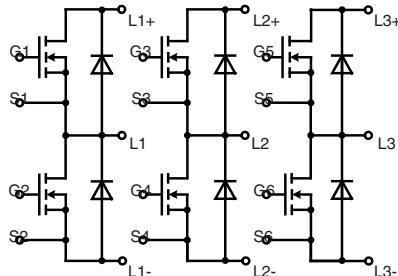


## Three phase full Bridge

with Trench MOSFETs  
in DCB isolated high current package

$V_{DSS}$  = 150 V  
 $I_{D25}$  = 50 A  
 $R_{DSon\ typ.}$  = 19 mΩ



### MOSFETs

Symbol	Conditions	Maximum Ratings		
$V_{DSS}$	$T_{VJ} = 25^\circ C$ to $150^\circ C$		150	V
$V_{GS}$	continuous		$\pm 15$	V
	transient		$\pm 20$	V
$I_{D25}$	$T_C = 25^\circ C$		50	A
$I_{D90}$	$T_C = 90^\circ C$		38	A
$I_{D110}$	$T_C = 110^\circ C$		33	A
$I_{F25}$	$T_C = 25^\circ C$ (diode)		150	A
$I_{F90}$	$T_C = 90^\circ C$ (diode)		85	A
$I_{F110}$	$T_C = 110^\circ C$ (diode)		65	A

### Symbol Conditions

### Characteristic Values

( $T_{VJ} = 25^\circ C$ , unless otherwise specified)

		min.	typ.	max.
$R_{DSon}$ <sup>1)</sup>	on chip level at $V_{GS} = 10 V$ ; $I_D = 38 A$		19 38	24 mΩ
$V_{GS(th)}$	$V_{DS} = 20 V$ ; $I_D = 1 mA$	2.5		4.5 V
$I_{DSS}$	$V_{DS} = V_{DSS}$ ; $V_{GS} = 0 V$		0.5	5 μA mA
$I_{GSS}$	$V_{GS} = \pm 20 V$ ; $V_{DS} = 0 V$			0.2 μA
$Q_g$ $Q_{gs}$ $Q_{gd}$	$V_{GS} = 10 V$ ; $V_{DS} = 75 V$ ; $I_D = 38 A$		97 29 30	nC nC nC
$C_{iss}$ $C_{oss}$ $C_{rss}$	$V_{GS} = 10 V$ ; $V_{DS} = 25 V$ ; $f = 1 MHz$		5800 490 85	pF pF pF
$t_{d(on)}$ $t_r$ $t_{d(off)}$ $t_f$ $E_{on}$ $E_{off}$ $E_{recoff}$	inductive load $V_{GS} = 10 V$ ; $V_{DS} = 75 V$ $I_D = 38 A$ ; $R_{G(on)} = 39 \Omega$ ; $R_{G(off)} = 4.7 \Omega$ $T_J = 125^\circ C$		120 50 100 25 0.25 0.05 0.02	ns ns ns ns mJ mJ mJ
$R_{thJC}$ $R_{thJH}$	with heat transfer paste (IXYS test setup)		1.3	1.0 K/W 1.6 K/W

<sup>1)</sup>  $V_{DS} = I_D \cdot (R_{DS(on)} + 2R_{Pin\ to\ Chip})$

### Applications

#### AC drives

- in automobiles
  - electric power steering
  - starter generator
- in industrial vehicles
  - propulsion drives
  - fork lift drives
- in battery supplied equipment

### Features

- MOSFETs in trench technology:
  - low RDSon
  - optimized intrinsic reverse diode
- package:
  - high level of integration
  - high current capability
  - aux. terminals for MOSFET control
  - terminals for soldering or welding connections
  - isolated DCB ceramic base plate with optimized heat transfer
- Space and weight savings

**Source-Drain Diode**

Symbol	Conditions	Characteristic Values		
		(T <sub>J</sub> = 25°C, unless otherwise specified)		
		min.	typ.	max.
V <sub>SD</sub>	(diode) I <sub>F</sub> = 38 A; V <sub>GS</sub> = 0 V	0.85	1.0	V
t <sub>rr</sub> Q <sub>RM</sub> I <sub>RM</sub>	I <sub>F</sub> = 38 A; -dI <sub>F</sub> /dt = 900 A/μs; R <sub>G(on)</sub> = 39 Ω; V <sub>R</sub> = 75 V; T <sub>VJ</sub> = 125°C	65 1.6 40		ns μC A

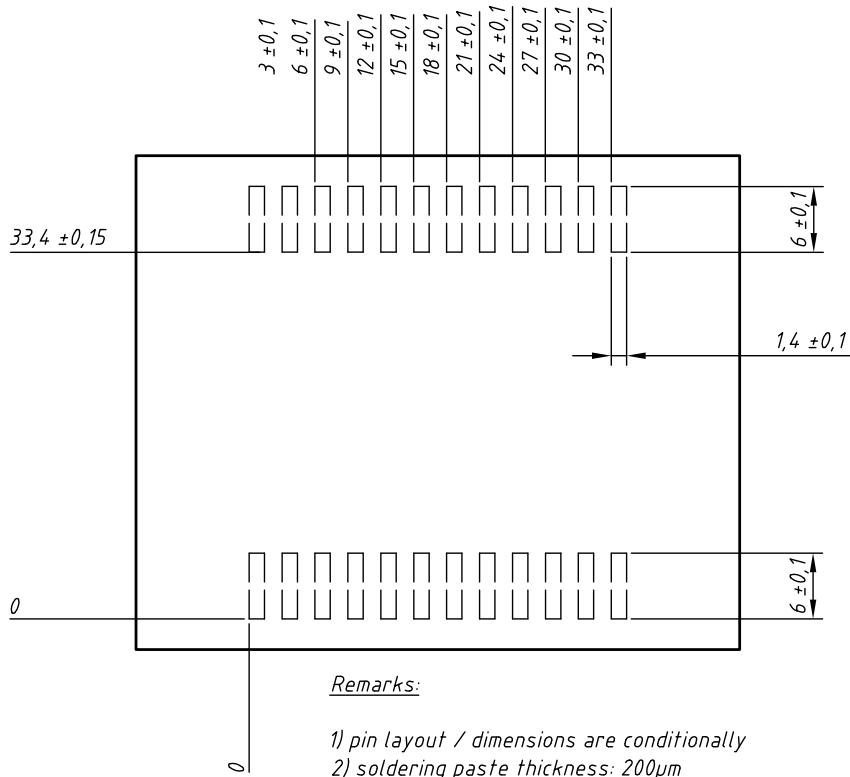
**Component**

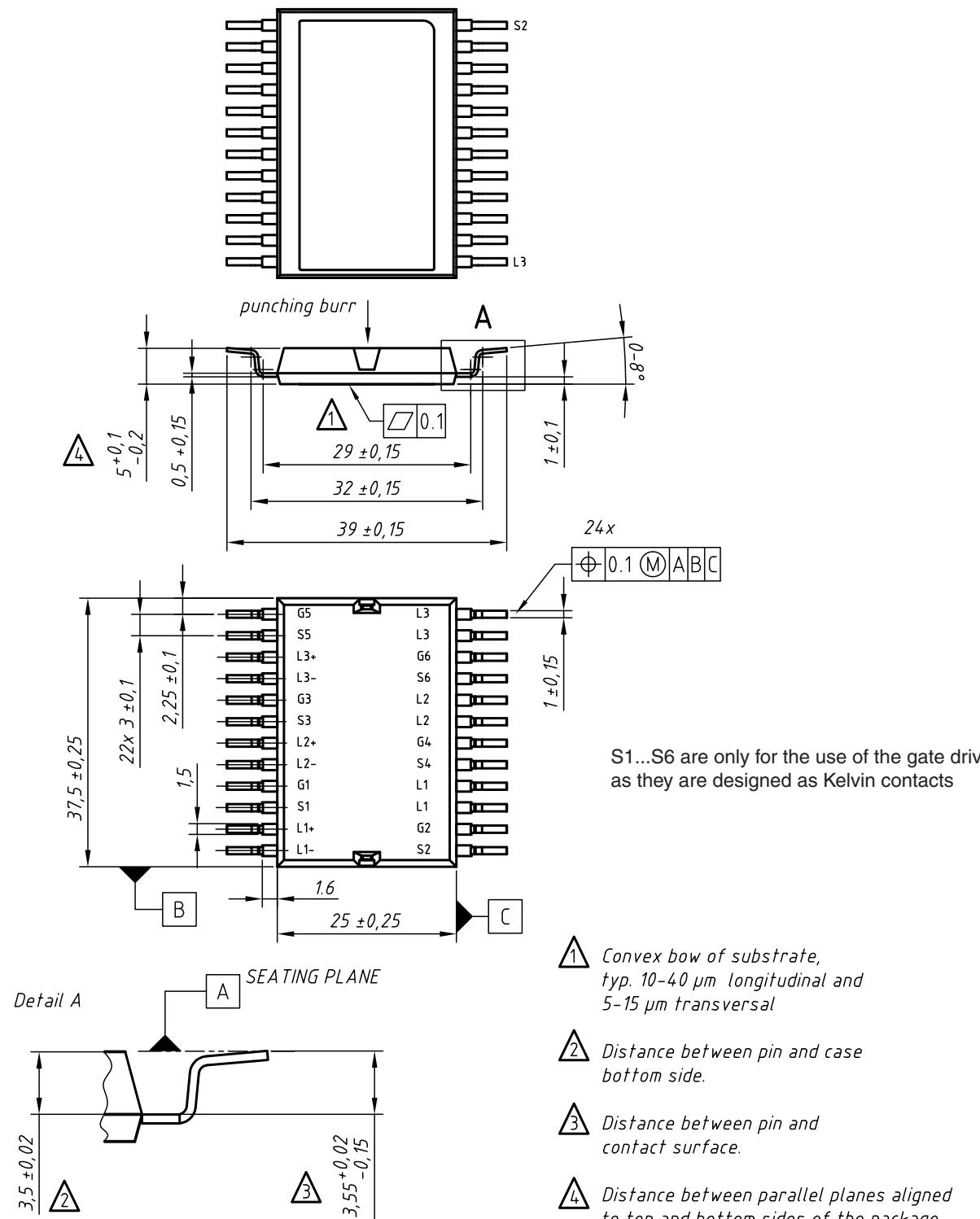
Symbol	Conditions	Maximum Ratings		
I <sub>RMS</sub>	per pin in main current paths (L+, L-, N-, L1, L2, L3) may be additionally limited by external connections 2 pins for output L1, L2, L3	75	A	
T <sub>J</sub>		-55...+175	°C	
T <sub>stg</sub>		-55...+125	°C	
V <sub>ISOL</sub>	I <sub>ISOL</sub> ≤ 1 mA, 50/60 Hz, f = 1 minute	1000	V~	
F <sub>c</sub>	mounting force with clip	50 - 250	N	

Symbol	Conditions	Characteristic Values		
		min.	typ.	max.
R <sub>pin to chip</sub> <sup>1)</sup>	L+ to L1/L2/L3 or L- to L1/L2/L3		0.9	mΩ
C <sub>P</sub>	coupling capacity between shorted pins and back side metallization		160	pF
<b>Weight</b>			13	g

<sup>1)</sup> V<sub>DS</sub> = I<sub>D</sub>·(R<sub>DS(on)</sub> + 2R<sub>Pin to Chip</sub>)

Recommended printed circuit board lay-out



**contact pin:**

- galv. tin plating, per pin side: Sn 10...25 µm, undercoating Ni 0,2...1 µm
- stamping edges may be free of tin
- puching burr:  $\leq 0,05\text{mm}$

Leads	Ordering	Part Name & Packing Unit Marking	Part Marking	Delivering Mode	Base Qty.	Ordering Code
SMD	Standard	GMM 3x60-015X2 - SMD	GMM 3x60-015X2	Tube	13	518037

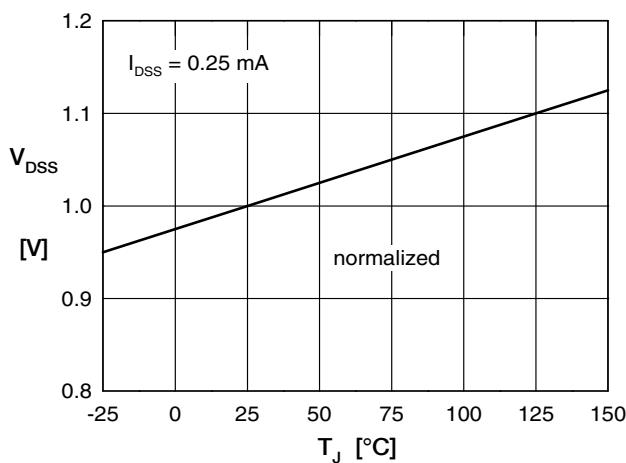


Fig.1 Drain source breakdown voltage  
 $V_{DSS}$  vs. junction temperature  $T_{VJ}$

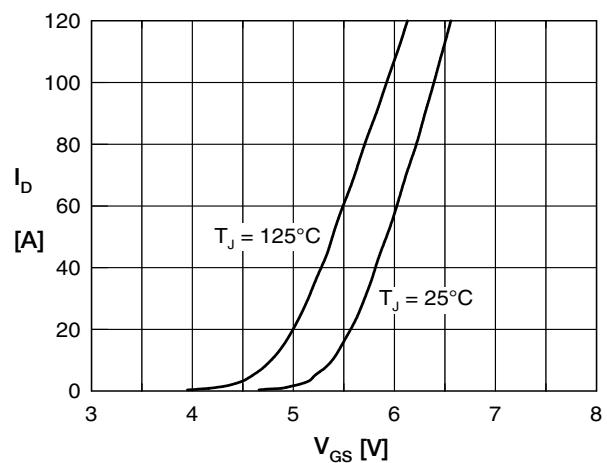


Fig. 2 Typ. transfer characteristics

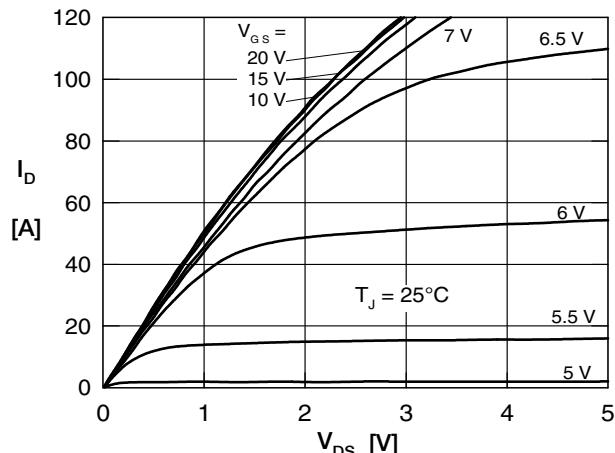


Fig. 3 Typ. output characteristics

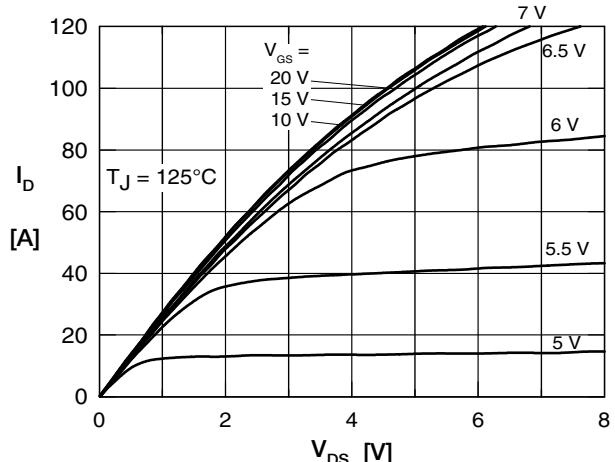


Fig. 4 Typ. output characteristics

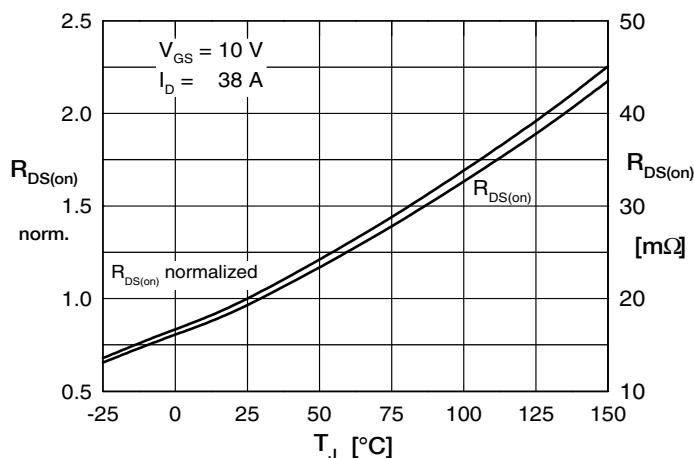


Fig.5 Drain source on-state resistance  
 $R_{DS(on)}$  versus junction temperature  $T_{VJ}$

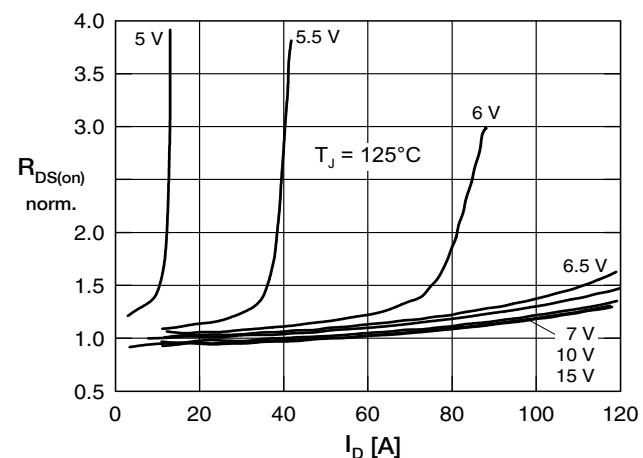


Fig. 6 Drain source on-state resistance  
 $R_{DS(on)}$  versus  $I_D$

IXYS reserves the right to change limits, test conditions and dimensions.

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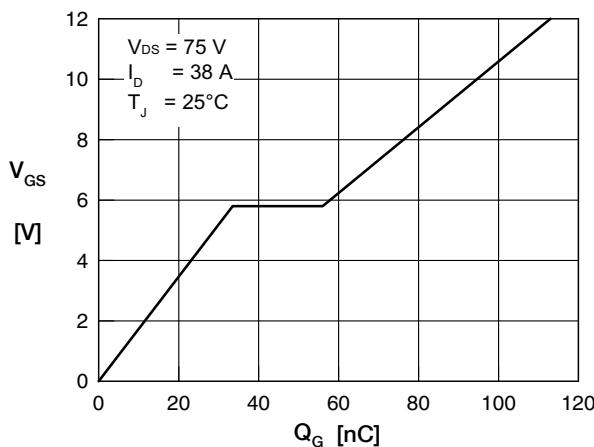


Fig. 7 Typical turn on gate charge

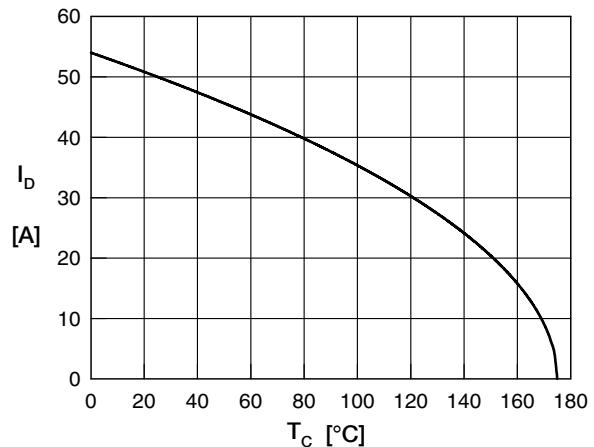


Fig. 8 Drain current  $I_D$  vs. case temperature  $T_C$

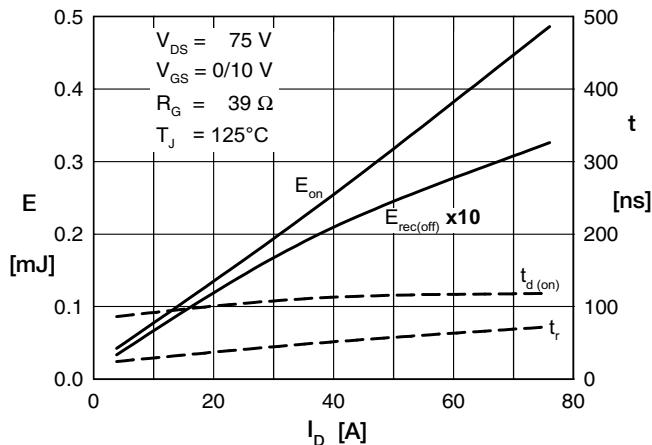


Fig. 9 Typ. turn-on energy and switching times versus drain current, inductive switching

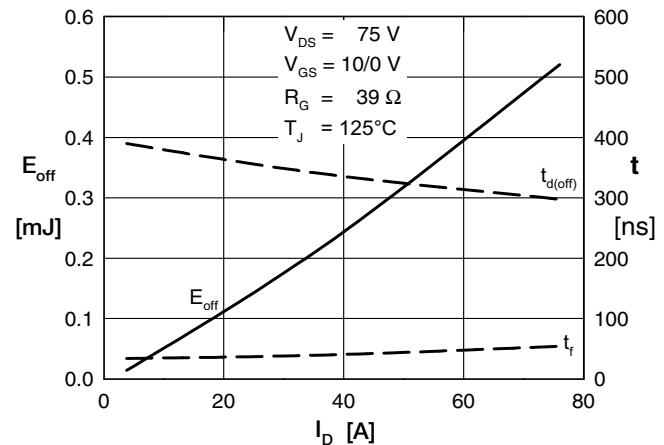


Fig. 10 Typ. turn-off energy and switching times versus drain-current, inductive switching

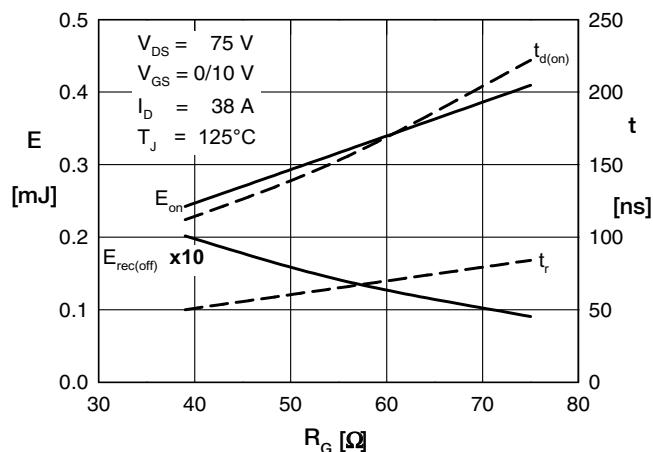


Fig. 11 Typ. turn-on energy and switching times versus gate resistor, induktive switching

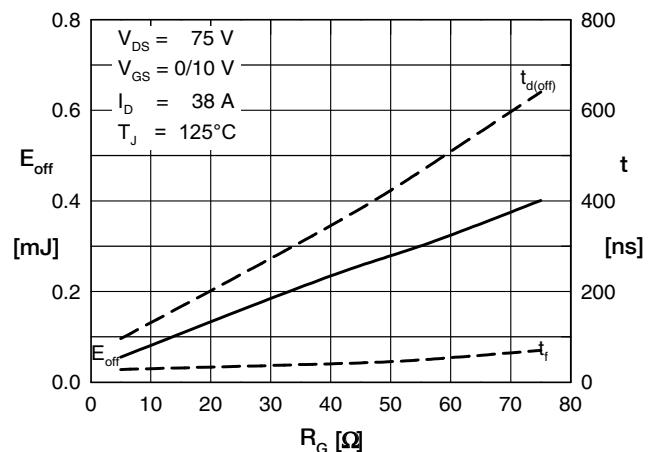


Fig. 12 Typ. turn-off energy and switching times versus gate resistor, induktive switching

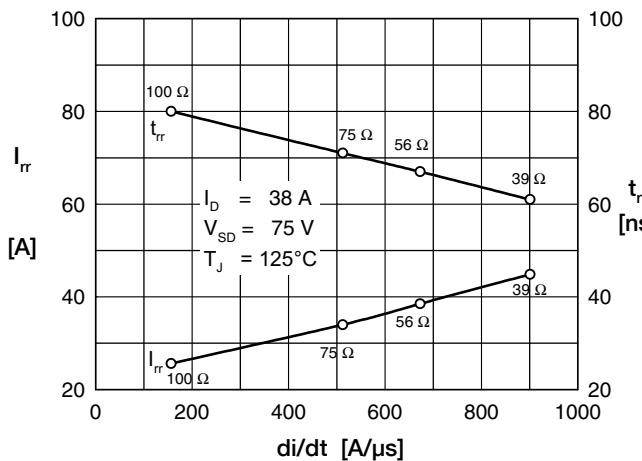


Fig. 13 Typ. reverse recovery characteristics

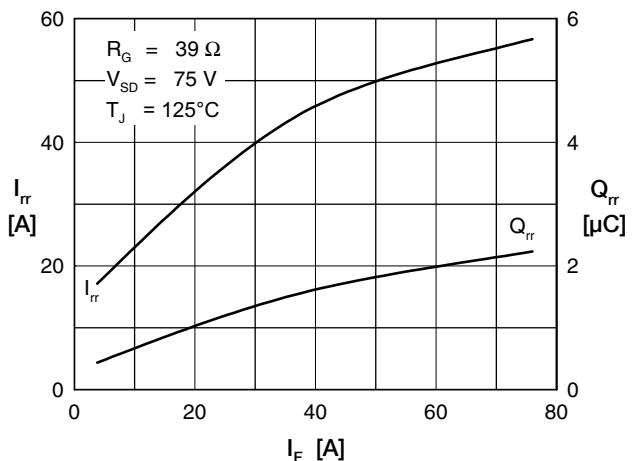


Fig. 14 Typ. reverse recovery characteristics

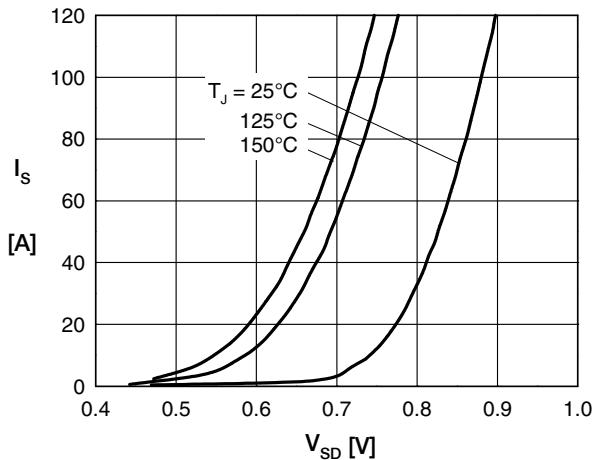
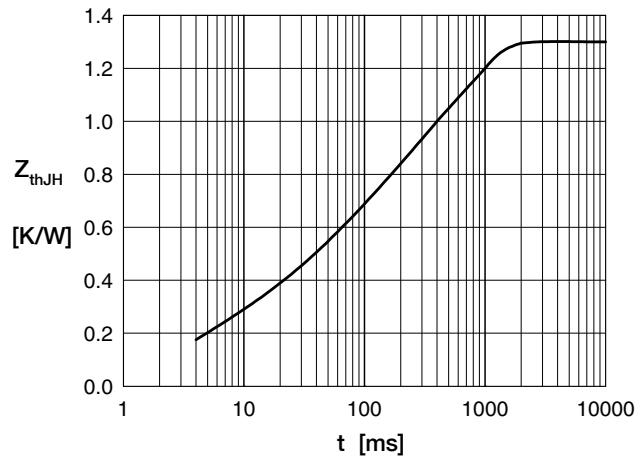
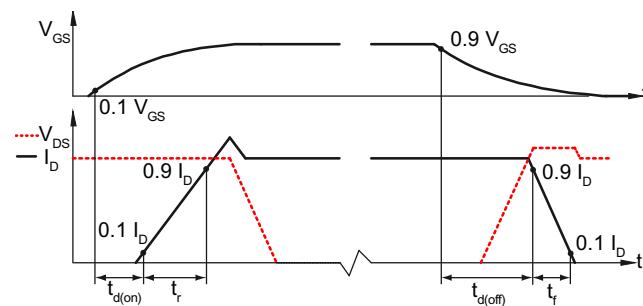
Fig. 15 Source current  $I_S$  versus source drain voltage  $V_{SD}$  (body diode)Fig. 16 Typ. thermal impedance junction to heatsink  $Z_{thJH}$  with heat transfer paste (IXYS test setup)

Fig. 17 Definition of switching times